

Technical Procedure for Scanning Electron Microscope/ Energy Dispersive X-Ray System (SEM/EDX) for GSR Casework

1.0 Purpose – This technical procedure shall be followed for the operation of the Scanning Electron Microscope/Energy Dispersive X-Ray System (SEM/EDX). This procedure shall be used for GSR casework.

2.0 Scope – This procedure applies to the EVO MA 15/Oxford and the LEO/Oxford Systems. These instruments are used for high resolution and magnification imaging with enhanced depth of field for trace evidence and non-destructive elemental analysis of gunshot residue particles, paint, metals, powders, and other trace particulate material.

3.0 Definitions – N/A

4.0 Equipment, Materials, and Reagents

4.1 Equipment

- EVO MA 15 Scanning Electron Microscope
- LEO 1450 Variable Pressure Scanning Electron Microscope
- Oxford Energy Dispersive X-ray System (SDD Detector)

4.2 Materials

- Mounting tweezers for SEM lifts
- Kimwipes
- Nitrile gloves
- Adhesive lifts with carbon-backed tape for blank standard
- Stainless Steel 316 Standard
- PLANO GSR Standard
- Manganese (Mn) / Rhodium (Rh) Standard
- Cobalt (Co) / Rhodium (Rh) Standard
- Manganese Standard
- Nitrogen gas, compressed (Purity Grade 5.0)

4.3 Reagents – N/A

5.0 Procedure

5.1 EVO/Oxford or LEO/Oxford SEM/EDX

5.1.1 SEM Start-Up Procedure & Loading of Samples

5.1.1.1 Press green “ON” button on microscope and turn on computer.

5.1.1.2 Load the SmartSEM software.

- 5.1.1.3 Open RemCon32 software.
- 5.1.1.4 Verify stage is initialized. If not initialized, remove sample holder and select Stage Initialize.
- 5.1.1.5 Using mounting tweezers, place samples in the holder and note position of each sample. Tighten the screws on the holder for each mounting position. Place the holder back on the stage, ensuring that the flat edge of the mount is against the flat area of the stage.
- 5.1.1.6 Close the SEM sample chamber and select “pump.” Allow system to reach vacuum.
- 5.1.1.7 Turn on the Extra High Tension (EHT) and Filament.
- 5.1.1.8 Adjust saturation of the filament slightly below or at the second crossover.
- 5.1.1.9 Adjust the working parameters of the instrument as necessary by accessing Tools through the User Toolbar and/or use of control panel with rotary controls.

5.1.2 Setting up a GSR Analysis in Oxford

- 5.1.2.1 Load INCA Software. Select GSR (LEO) or Feature (EVO) Tab.
- 5.1.2.2 Identify the Project name and sample information for each adhesive lift in the holder.
- 5.1.2.3 Go to the Recipe tab. Create a database and select “NC Crime Lab GSR” recipe. ***NOTE* Do not “Lock” or “Embed database within the project file.”**
- 5.1.2.4 Go to the Microscope tab. Set the stage point to the Mn or Co standard. Increase the Mag to 766 and deadtime to approximately 40%.
- 5.1.2.5 Go to the Quant Optimization tab. Choose Mn or Co standard and acquire a spectrum.
- 5.1.2.6 Go to the Area Layout, select areas tab, and highlight the adhesive lift associated with each sample.
- 5.1.2.7 Go to the GSR or Feature Detection tab. Select Calibration and Mn/Rh standard or Co/Rh standard. Acquire a spectrum and optimize the working parameters to between 145 and 255.
- 5.1.2.8 Run automated analysis.

5.1.3 Particle Relocation & Identification

- Page 3 of 9

5.1.5.4 Close all windows in INCA software and shut down Oxford computer.

5.1.6 Performance Verification for New Instrument Set-Up

5.1.6.1 A new SEM with EDX detector shall be installed by a certified engineer according to the manufacturer's guidelines.

5.1.6.2 Spectra shall be obtained from a Manganese/Rhodium Standard and/or Cobalt/Rhodium Standard, and a Stainless Steel 316 Standard.

5.1.6.3 An analysis shall be performed on a PLANO GSR Standard and then compared to the known amount of GSR particle's on that standard.

5.1.7 Standards & Controls - This instrument requires the use of a Manganese/Rhodium standard or a Cobalt/Rhodium standard with a Manganese standard for performance checks. In addition a Stainless Steel 316 Standard shall be used for performance checks and verifications. The PLANO GSR standard is used for performance verifications. These standards have no special storage requirements.

5.1.8 Maintenance - Routine maintenance shall be performed such as changing pump oil, checking liquid chiller status (LEO), and replacing a filament. Any maintenance performed shall be documented in the maintenance log for that particular instrument.

5.2 Sampling and Sample Selection – No sampling is performed. When sample selection occurs, it shall be based on the Forensic Scientist's training and experience

5.3 Calculations - N/A

5.4 Uncertainty of measurement - N/A

6.0 Limitations – N/A

7.0 Safety

7.1 The greatest safety concern is radiation from the X-ray tube. The x-ray system is monitored for leaks on a regular basis.

7.2 There is a high voltage/current safety concern which can cause electrocution. Avoid contact with any live circuitry components. Potentially lethal voltages exist with the high voltage x-ray supply.

8.0 References

ASTM Standard E 1588 – 95 (2001), "Standard Guide for Gunshot Residue Analysis by Scanning Electron Microscopy/ Energy—Dispersive Spectroscopy." ASTM International, West Conshohocken, PA, 2001, www.astm.org.

Andrasko, J. "Detection of Gunshot Residue on Hands by Scanning Electron Microscopy." *Journal of Forensic Sciences* 22.2 (1977): 279-287.

DeGaetano, Douglas, et al. "A Comparison of Three Techniques Developed for Sampling and Analysis of Gunshot Residue by Scanning Electron Microscopy/Energy Dispersive X-Ray Analysis (SEM/EDX)." *Journal of Forensic Sciences* 37.1 (1992): 281-300.

Nesbitt, R.S., et al. "Detection of Gunshot Residue by Use of the Scanning Electron Microscope." *Journal of Forensic Sciences* 21.3 (1976): 595-610.

Wolten, G.M., et al. "Final Report on Particle Analysis for Gunshot Residue Detection." The Aerospace Corporation, ATR-77 (7915)-3, 1977.

9.0 Records

- ASPEX SEM/EDX Performance Check Log
- Maintenance Log
- Results For Instrumental Analysis Of Evidence For Gunshot Residue

10.0 Attachments

- APPENDIX 1: Guidelines for GSR Acquisition parameters.

Revision History		
Effective Date	Version Number	Reason
09/17/2012	1	Original ISO Document
02/01/2013	2	Request for Instrumental Analysis of Evidence for Gunshot Residue was added as a record. Revised title for Attachment 1 and measure dwell time.
09/30/2013	3	5.1.4 - Removed from performance check that it shall be performed by first person to use the instrument
10/18/2013	4	Added issuing authority to header
09/05/2014	5	Updated header to Physical Evidence Section – Trace Unit, issuing authority to Physical Evidence Section Forensic Scientist Manager. 5.1.1.2, 5.1.1.3, 5.1.2.3, 5.1.2.5, 5.1.2.7, 5.1.2.8, 5.1.2.10, 5.1.3, 5.1.3.1, 5.1.3.2, and 5.1.3.5 were updated to clarify the instructions for use. Added Appendix 1. Removed: 5.1.1.1, 5.1.1.4, 5.1.1.5, 5.1.1.6, 5.1.3.2, 5.1.3.4. Moved instructions to SEM Training.
07/01/2016	6	Added Instrumentation for GSR Analysis (Section 5.2). GSR samples can now be examined on the LEO/Oxford SEM/EDX.
07/27/2018	7	Updated 2.0, 4.1, 4.2, 5.1, to reflect new equipment and materials. The following were updated to clarify instructions for use on current instrumentation and software: 5.1.1.1, 5.1.1.3, 5.1.1.4, 5.1.1.6, 5.1.1.9, 5.1.2.1, 5.1.2.4, 5.1.2.5, 5.1.2.7, 5.1.4.1, 5.1.4.2, 5.1.4.3, 5.1.4.4, 5.1.4.5, 5.1.4.6, 5.1.4.7, 5.1.5.1, 5.1.5.2, 5.1.5.3, 5.1.5.4, 5.1.6.2, 5.1.6.3, 5.1.7, 5.1.8. Edited Appendix 1 to show parameters as they appear in current software. Removed information regarding ASPEX instrument that is no longer in service: 2.0, 4.1, 4.2, and 5.1 ASPEX, 5.1.6.2, 10.0. Deleted extra spacing: 5.1.2.6, 5.1.3.3, and between 5.1.6 and 5.1.7. Misspelling 5.1.1.8

APPENDIX 1: Guidelines for GSR Acquisition parameters

The default parameters for GSR are saved as recipe “NC Crime Lab GSR” file in INCA software.

The screenshot displays the INCA software interface for GSR acquisition parameters, organized into four main sections:

- Field setup**: Includes resolution options (512 x 384, 1024 x 768, 2048 x 1536), a signal dropdown menu set to "BSE", and dwell time settings for the first (2) and second (10) pass images in microseconds. An "Advanced" button is located at the bottom right of this section.
- Features**: Contains input fields for Magnification (766), Smallest expected feature width (0.7031 μm), and Ignore features smaller than area (1 pixels (0.40 μm ecd)). A checkbox for "Guard Zone" is set to 50 pixels (17.58 μm). A "Read Microscope" button is present.
- Gray Image Processing (before thresholding)**: Features a dropdown menu set to "Median" and a table for processing steps.
- Binary Image Processing (after thresholding)**: Features a dropdown menu set to "Erode" and a table for processing steps.

Each processing table has two columns: "Process" and "Argument".

Measurement settings for ED analysis

☐ Morphological measurements only

Passes: 1

Pass 1 Livetime (secs): 2.00

Pass 2 Additional livetime (secs): 5.00

Process time: 5

Spectrum range (keV): 0 - 20

Number of channels: 1K eV/channel: 20

☐ Center of longest chord

☒ Whole Feature

Restore

Field Termination		
Total features limit in a Field	<input type="text" value="0"/>	Rank <input type="text" value="Char.GSR"/>
Total features limit in a rank	<input type="text" value="0"/>	
Total time spent in a Field (minutes)	<input type="text" value="0.00"/>	

Area Termination Checked once per field		
Total features limit in an Area	<input type="text" value="0"/>	Rank <input type="text" value="Char.GSR"/>
Total features limit in a rank	<input type="text" value="0"/>	
Total time spent in an Area (minutes)	<input type="text" value="0.00"/>	

Sample Termination Checked once per field		
Total features limit in a Sample	<input type="text" value="4000"/>	Rank <input type="text" value="Char.GSR"/>
Total features limit in a rank	<input type="text" value="100"/>	
Total time spent in a Sample (minutes)	<input type="text" value="600.00"/>	

Save options	End of run
<input checked="" type="checkbox"/> Save spectrum for each feature	<input checked="" type="checkbox"/> Turn beam off
<input checked="" type="checkbox"/> Save diagram for each feature	<input checked="" type="checkbox"/> Turn filament off
<input checked="" type="checkbox"/> Save image for each field	